

**Search Notes**

Application/Control No.

09/766,270

Examiner

Chau Nguyen

Applicant(s)/Patent under  
Reexamination

SEKIDO ET AL.

Art Unit

2176

**SEARCHED**

| Class | Subclass | Date       | Examiner |
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| 715   | 522-523  | 9/28/2004  | CN       |
| 715   | 530      | 9/28/2004  | CN       |
| 715   | 531      | 9/29/2004  | CN       |
| 715   | 539      | 9/29/2004  | CN       |
| 715   | 540      | 9/29/2004  | CN       |
| 707   | 102      | 9/29/2004  | CN       |
| 715   | 522-523  | 11/22/2005 | CN       |
| 715   | 530-531  | 11/22/2005 | CN       |
| 715   | 539-540  | 11/22/2005 | CN       |
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**INTERFERENCE SEARCHED**

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|                                | DATE       | EXMR |
|--------------------------------|------------|------|
| East Reports                   | 09/28/2004 | CN   |
|                                | 9/29/2004  | CN   |
|                                | 10/4/2004  | CN   |
|                                | 10/12/2004 | CN   |
|                                | 10/20/2004 | CN   |
|                                | 10/21/2004 | CN   |
| Updated Search on East Reports | 11/22/2005 | CN   |
| NPL Search on IEEE Database    | 11/23/2005 | CN   |